

A DFT scheme to improve coverage of hard-to-detect faults in FinFET SRAMs

Cardoso Medeiros, Guilherme; **Gürsoy, Cemil Cem**; Fieback, Moritz; Wu, Lizhou; **Jenihhin, Maksim**; Taouil, Mottaqiallah; Hamdioui, Said 2020 Design, Automation & Test in Europe Conference & Exhibition (DATE), 9-13 March 2020, Grenoble, France : proceedings 2020 / p. 792-797 <https://doi.org/10.23919/DATE48585.2020.9116278>

Gate-level modelling of NBTI-induced delays under process variations

Copetti, Thiago; Cardoso Medeiros, Guilherme; Bolzani Poehls, Leticia; Vargas, Fabian; **Kostin, Sergei**; **Jenihhin, Maksim**; **Raik, Jaan**; **Ubar, Raimund-Johannes** LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguaçu, Brazil, 6th-9th April 2016 2016 / p. 75-80 : ill <http://dx.doi.org/10.1109/LATW.2016.7483343>

Modeling soft-error reliability under variability

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